

TC - 4ETI - CI : CAPTEURS INTELLIGENTS

L. LABRAK

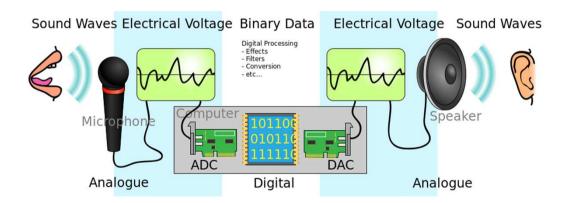






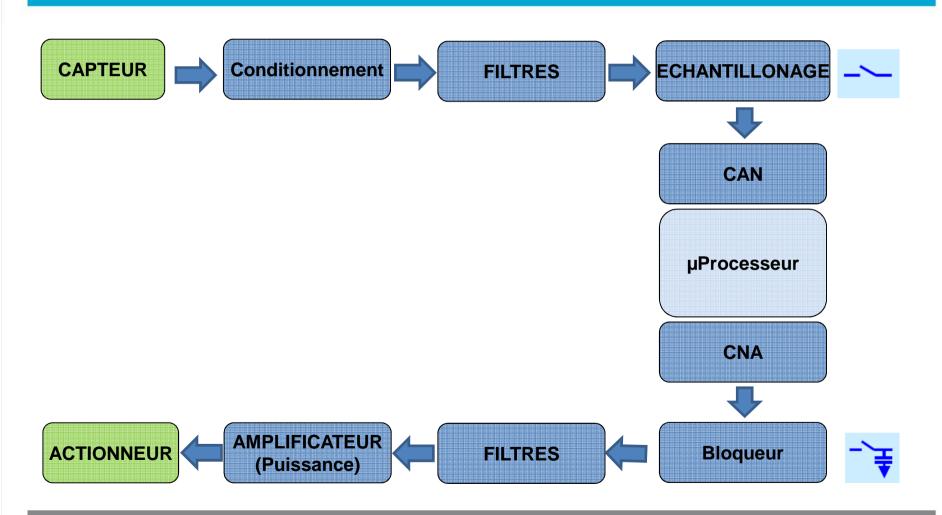
Section ETI : Sciences du Numérique

CONVERSIONS DES SIGNAUX



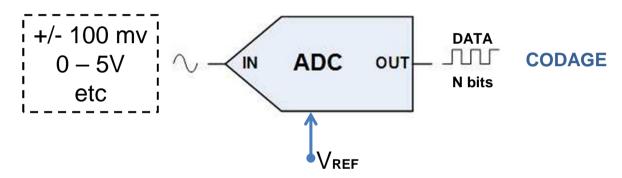
La chaine d'acquisition







Entrée : simple ou différentielle



CAN

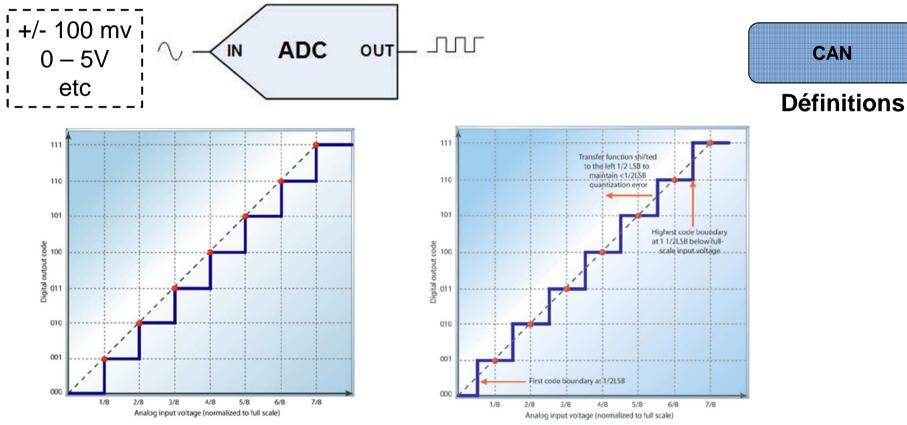
Définitions

Q (Quantum) ou LSB (Last Significant Bit) => Résolution

$$1 LSB = FSR/(2^n - 1)$$

Tension de pleine échelle (FSR) vs Tension de référence (VREF)

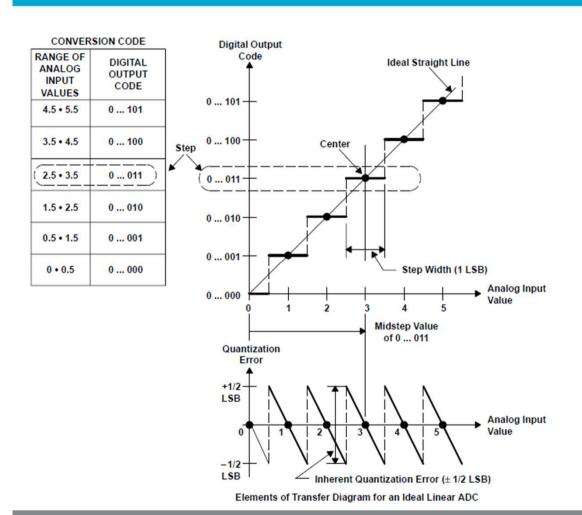


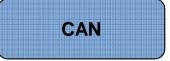


Caractéristique de transfert d'un CAN [1]

[1] Len Satller, Silicon labs, Application Notes



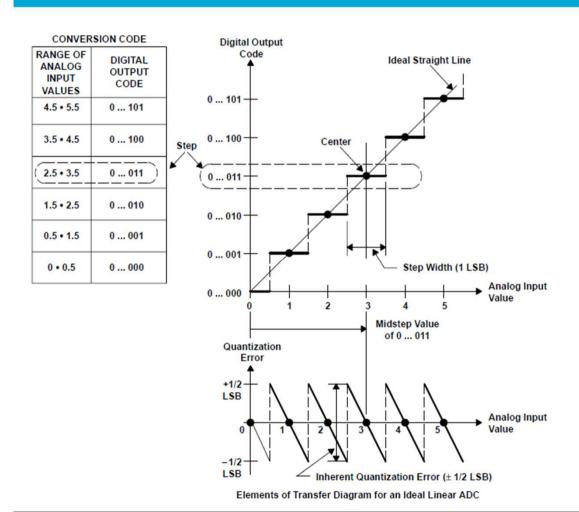




Erreur de quantification

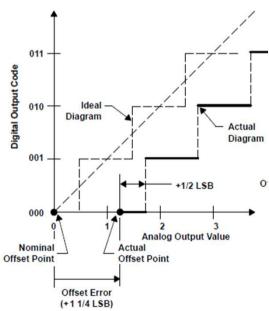
Comment la réduire ?





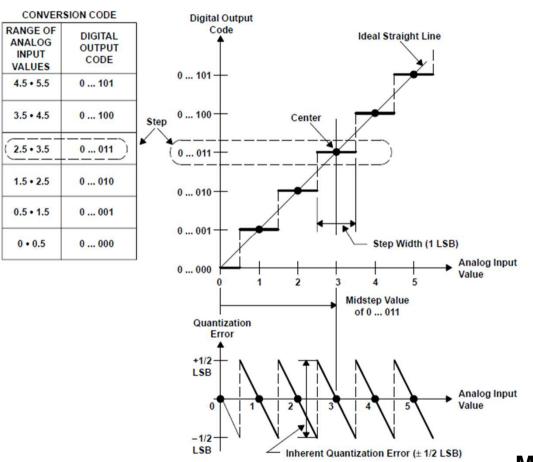


Erreur de décalage



Constante sur toute la plage

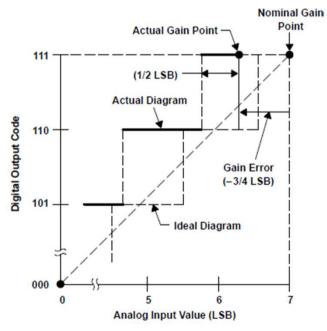




Elements of Transfer Diagram for an Ideal Linear ADC

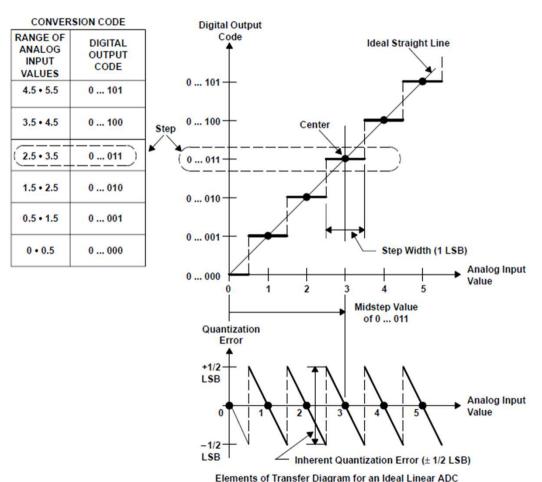


Erreur de Gain



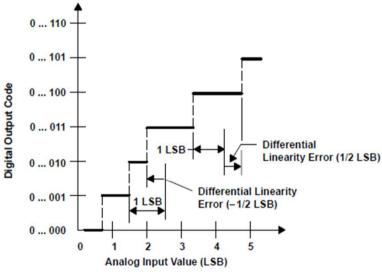
Mesurée sur la dernière transition





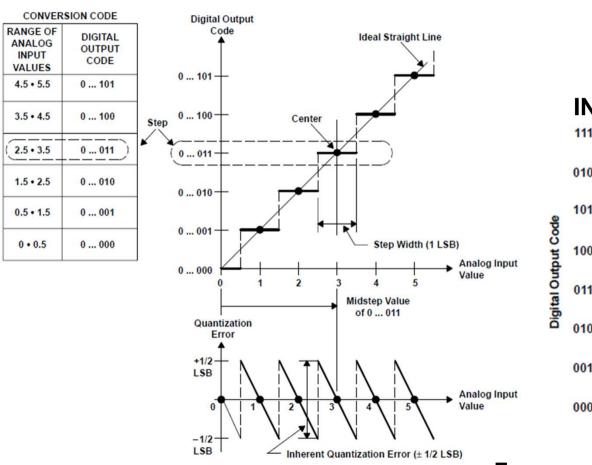


DNL: Differential Non Linearity



Peut induire code manquant

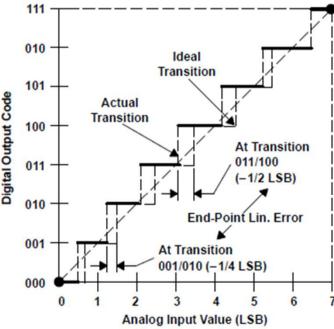




Elements of Transfer Diagram for an Ideal Linear ADC



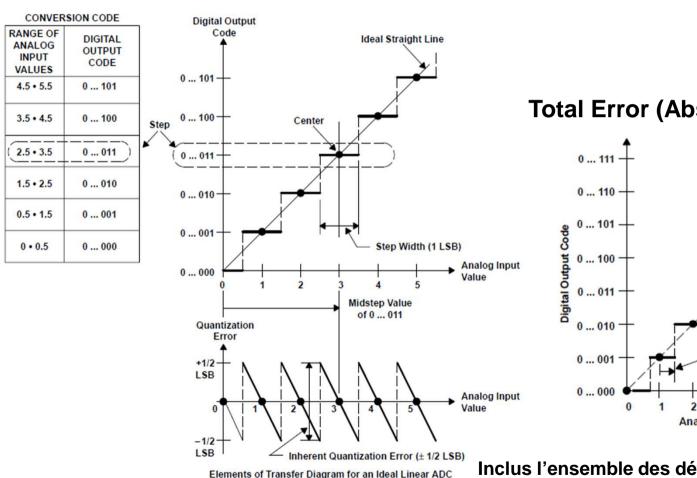
INL: Integral Non Linearity



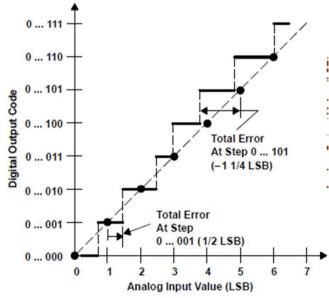
Erreur cumulative sur chaque transition



CAN



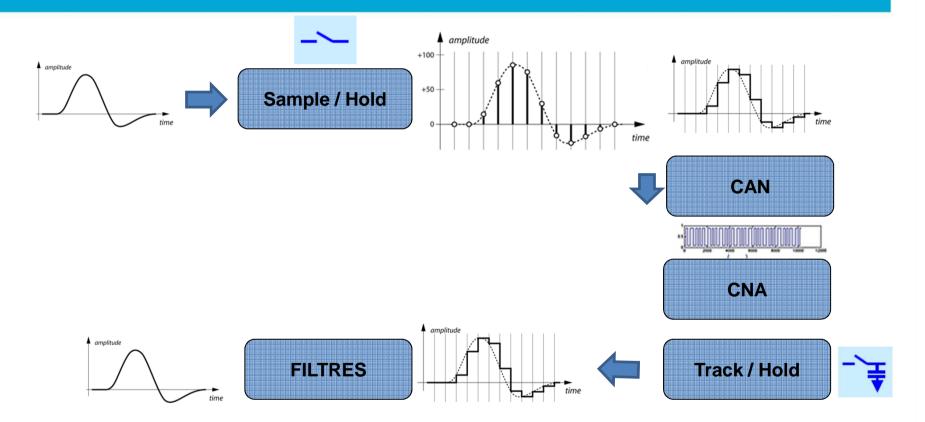




Inclus l'ensemble des défauts à chaque transition

Retour sur l'échantillonage

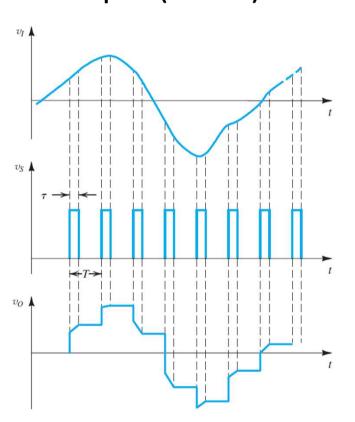


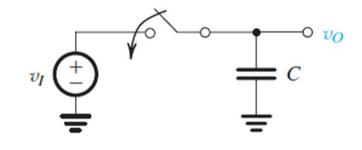


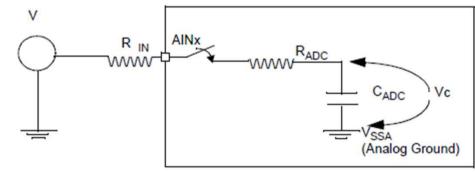
Retour sur l'échantillonnage

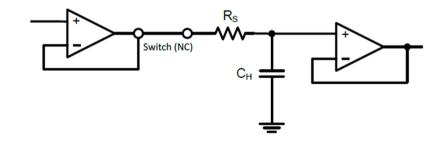


- Sample (Track) and Hold









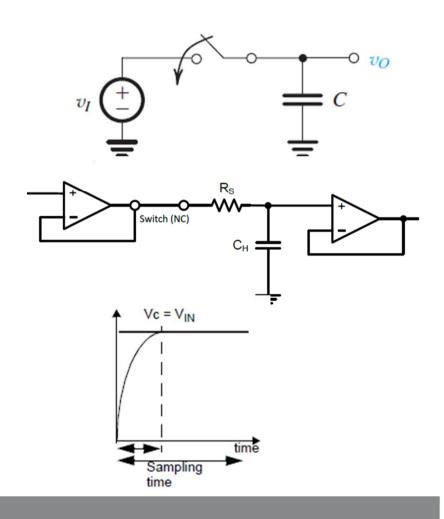
Retour sur l'échantillonnage



Acquisition Time (ta):

Temps nécessaire à la capacité C_H pour se charger à la valeur de la tension V_{IN} II dépend de 3 facteurs:

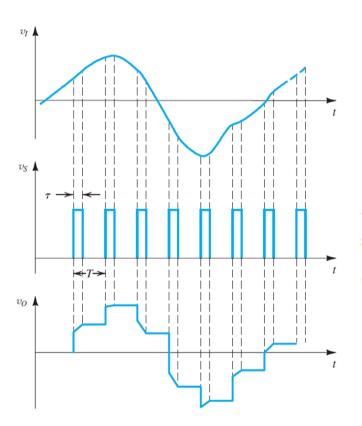
- 1. La constante de temps RC
- 2. Courant max de l'AOP
- 3. Slew rate de l'AOP

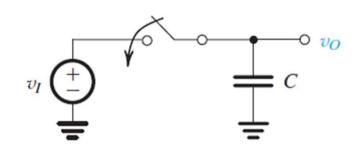


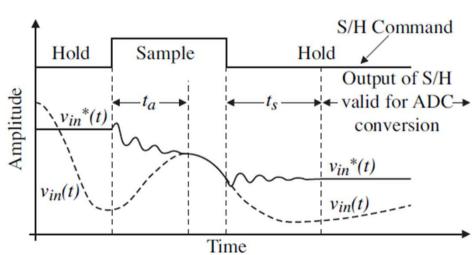
Retour sur l'échantillonage



Sample and Hold







Retour sur l'échantillonage



Incertitude sur l'ouverture :

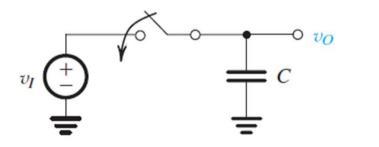
Variation du temps d'ouverture d'un échantillon à l'autre

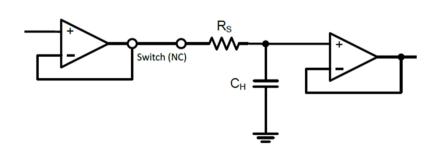
Temps d'établissement en mode bloqué :

Après application de la commande bloquage, il faut un certain temps pour atteindre le pourcentage d'erreur toléré 1%, 0.1%, 0.01%.

Offset:

Au moment du passage du blocage à l'échantillonnage (et inversement), il y a transfert de charge entre l'interrupteur (switch) et la capacité) => modification de la tension de sortie appelé pedestal error ou sample/hold offset

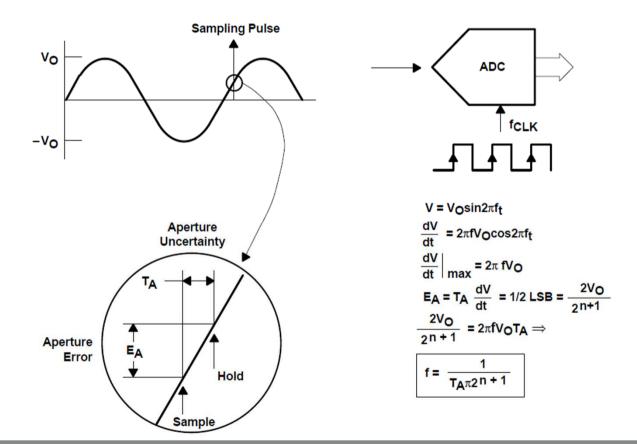




Retour sur l'échantillonnage



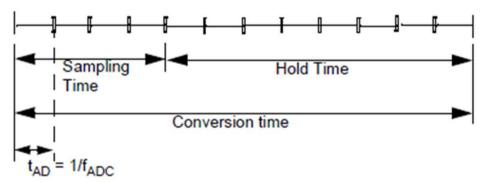
Sample and Hold : variation max et fréquence



Performances dynamiques



- Throughtput et temps de conversion
 - **100 MSPS** avec 13 clk => quelle est la fréquence d'horloge nécessaire?



- => 1/Throughput = NbrCycle* Tclk
- En déduire la fréquence max des signaux d'entrée

ADC0 du C8051F020



Table 5.1. 12-Bit ADC0 Electrical Characteristics (C8051F020/1)

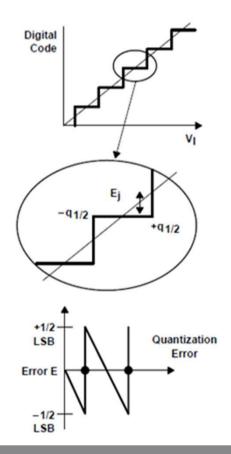
VDD = 3.0V, AV+ = 3.0V, VREF = 2.40V (REFBE=0), PGA Gain = 1, -40°C to +85°C unless otherwise specified

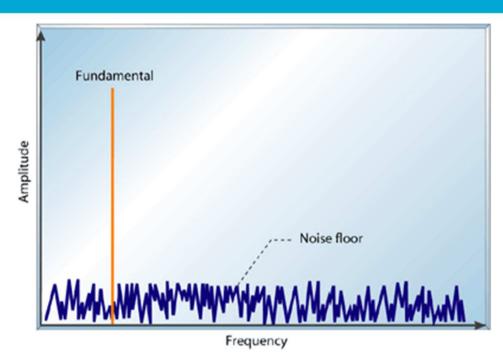
| PARAMETER | CONDITIONS | MIN | TYP | MAX | UNITS |
|---|------------------------------------|------------|-----------|--------|--------|
| DC ACCURACY | | | | | |
| Resolution | | 12 | | | bits |
| Integral Nonlinearity | | | | ±1 | LSB |
| Differential Nonlinearity | Guaranteed Monotonic | | | ±1 | LSB |
| Offset Error | | | -3±1 | | LSB |
| Full Scale Error | Differential mode | | -7±3 | | LSB |
| Offset Temperature Coefficient | | | ±0.25 | | ppm/°C |
| DYNAMIC PERFORMANCE (I | kHz sine-wave input, 0 to 1 dE | below Full | Scale, 10 | 0 ksps | |
| Signal-to-Noise Plus Distortion | | 66 | | | dB |
| Total Harmonic Distortion | Up to the 5 th harmonic | | -75 | | dB |
| Spurious-Free Dynamic Range | | | 80 | | dB |
| CONVERSION RATE | | • | | | |
| SAR Clock Frequency | | | | 2.5 | MHz |
| Conversion Time in SAR Clocks | | 16 | | | clocks |
| Track/Hold Acquisition Time | | 1.5 | | | μs |
| Throughput Rate | | | | 100 | ksps |
| NALOC DITUTO | • | | | • | |
| Input Voltage Range | Single-ended operation | 0 | | VREF | V |
| *Common-mode Voltage Range | Differential operation | AGND | | AV+ | V |
| Input Capacitance | | | 10 | | pF |
| TEMPERATURE SENSOR | • | | | | |
| Nonlinearity | | -1.0 | | +1.0 | °C |
| Absolute Accuracy | | | ±3 | | °C |
| Gain | PGA Gain = 1 | | 2.86 | | mV/°C |
| Offset | PGA Gain = 1, Temp = 0°C | | 0.776 | | V |
| POWER SPECIFICATIONS | | | | | |
| Power Supply Current (AV+ sup- plied to ADC) | Operating Mode, 100 ksps | | 450 | 900 | μА |
| Power Supply Rejection | | | ±0.3 | | mV/V |

Performances dynamiques



- Le SNR



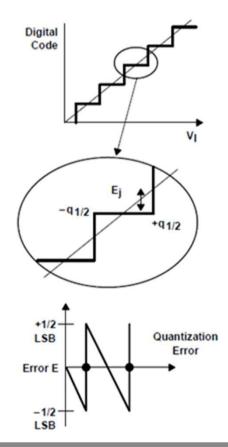


$$f_{eff} = \frac{1}{T} \int_0^T A^2 \sin^2 \omega t \, dt = \frac{A^2}{2}$$
$$E(\epsilon^2) = \frac{1}{q} \int_{-q/2}^{+q/2} \epsilon^2 d \, \epsilon = \frac{q^2}{12}$$

Performances dynamiques



- Le SNR



Error at the jth step

$$E_j = (V_j - V_l)$$

The mean square error over the step

$$\overline{E}_{j}^{2} = \frac{1}{q_{1}} \int_{-q/2}^{+q/2} E_{j}^{2} dE = \frac{q^{2}}{12}$$

Assuming equal steps, the total error is $\overline{N}^2 = q^2/12$ (Mean square quantization noise)

For an input sine wave $F(t) = A \sin \omega t$, the signal power

$$\overline{F}^{2}(t) = \frac{1}{2\pi} \int_{0}^{2\pi} A^{2} \sin^{2}\omega t \, d\omega t = \frac{A^{2}}{2}$$

and
$$q = \frac{2A}{2^n} = \frac{A}{2^{n-1}}$$

$$SNR = 10 Log \left(\frac{F^2}{n^2}\right) = 10 Log \left(\frac{A^2/2}{A^2/3 \times 2^n}\right)$$

$$SNR = 6.02n + 1.76 dB$$

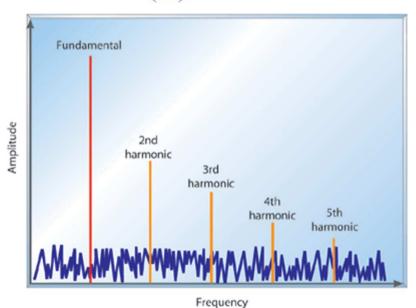
$$ENOB = \frac{SNR_{dB} - 1,76}{6.02}$$

Performances

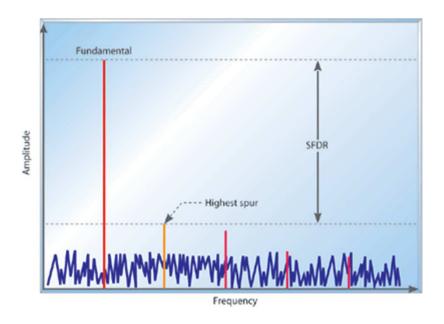


– Dynamiques : THD – SINAD - SFDR

$$SNR = 20\log\left(\frac{S}{N}\right),\,$$



THD =
$$20 \log \left(\frac{S}{D}\right)$$
 SINAD = $20 \log \left(\frac{S}{N+D}\right)$



ADC0 du C8051F020



Table 5.1. 12-Bit ADC0 Electrical Characteristics (C8051F020/1)

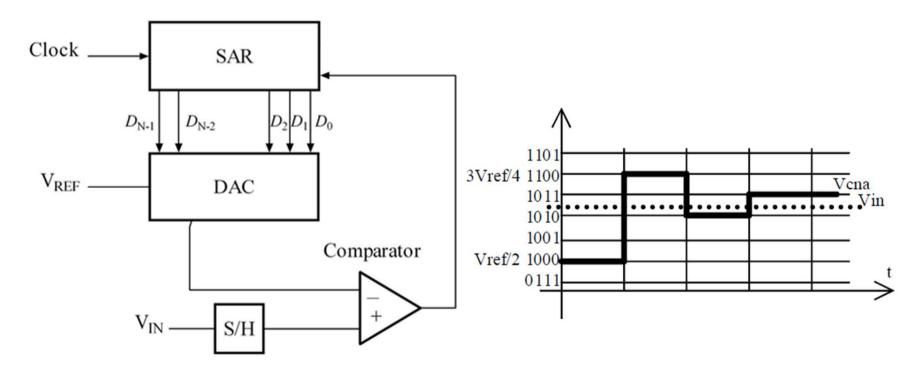
VDD = 3.0V, AV+ = 3.0V, VREF = 2.40V (REFBE=0), PGA Gain = 1, -40°C to +85°C unless otherwise specified

| PARAMETER | CONDITIONS | MIN | TYP | MAX | UNITS |
|---|------------------------------------|------------|-----------|--------|--------|
| DC ACCURACY | | | | | |
| Resolution | | | 12 | | bits |
| Integral Nonlinearity | | | | ±1 | LSB |
| Differential Nonlinearity | Guaranteed Monotonic | | | ±1 | LSB |
| Offset Error | | | -3±1 | | LSB |
| Full Scale Error | Differential mode | | -7±3 | | LSB |
| Offset Temperature Coefficient | | | ±0.25 | | ppm/°C |
| DYNAMIC PERFORMANCE (10 | kHz sine-wave input, 0 to 1 dE | below Full | scale, 10 | 0 ksps | |
| Signal-to-Noise Plus Distortion | | 66 | | | dB |
| Total Harmonic Distortion | Up to the 5 th harmonic | | -75 | | dB |
| Spurious-Free Dynamic Range | | | 80 | | dB |
| CONVERSION KATE | • | • | | | |
| SAR Clock Frequency | | | | 2.5 | MHz |
| Conversion Time in SAR Clocks | | 16 | | | clocks |
| Track/Hold Acquisition Time | | 1.5 | | | μs |
| Throughput Rate | | | | 100 | ksps |
| ANALOG INPUTS | | | | | |
| Input Voltage Range | Single-ended operation | 0 | | VREF | V |
| *Common-mode Voltage Range | Differential operation | AGND | | AV+ | V |
| Input Capacitance | | | 10 | | pF |
| TEMPERATURE SENSOR | | | | | |
| Nonlinearity | | -1.0 | | +1.0 | °C |
| Absolute Accuracy | | | ±3 | | °C |
| Gain | PGA Gain = 1 | | 2.86 | | mV/°C |
| Offset | PGA Gain = 1, Temp = 0°C | | 0.776 | | V |
| POWER SPECIFICATIONS | | | | | |
| Power Supply Current (AV+ sup- plied to ADC) | Operating Mode, 100 ksps | | 450 | 900 | μА |
| Power Supply Rejection | | | ±0.3 | | mV/V |

ARCHITECTURES: SAR

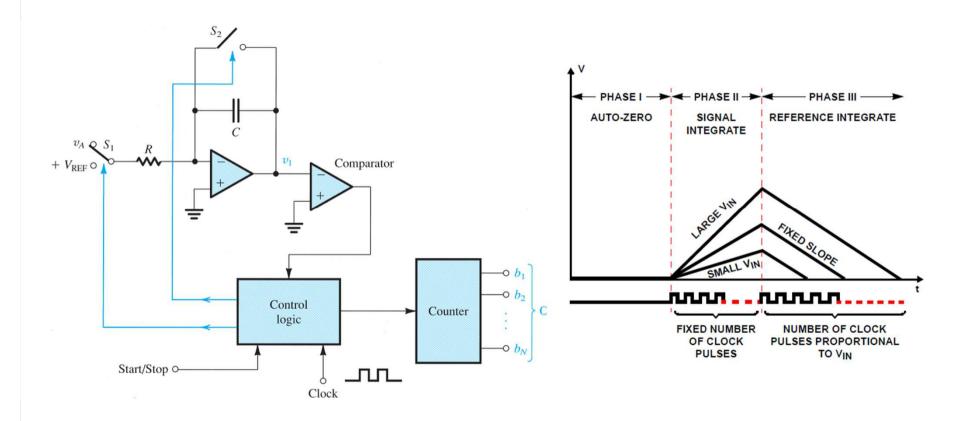


Registre à approximations successives



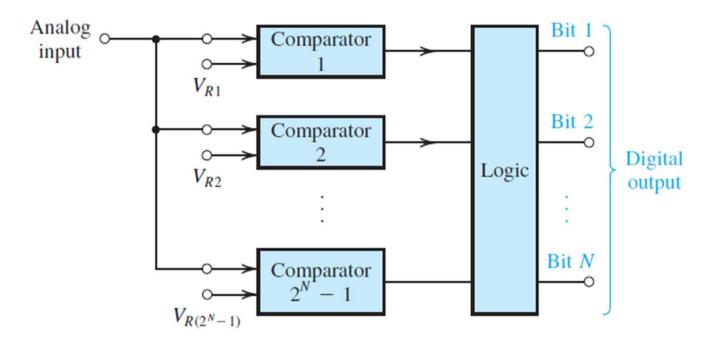
ARCHITECTURES: Double Rampe





ARCHITECTURES: Flash et Semi-Flash

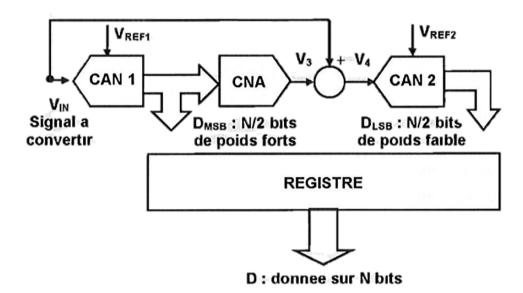




Le codeur détecte le nombre d'entrées au niveau 0 et code ce nombre sur N bits en sortie (A B C).

ARCHITECTURES: Flash et Semi-Flash

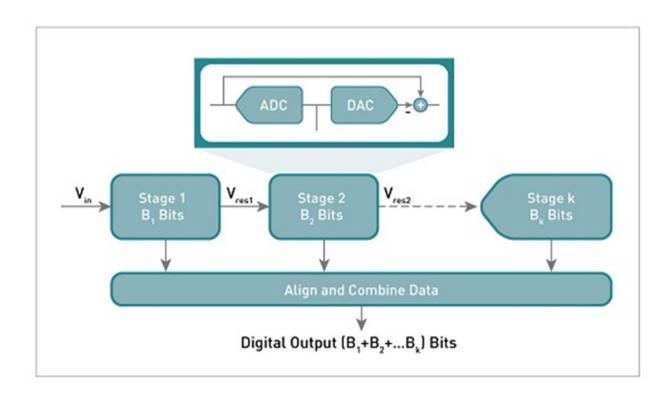




- Nous prenons le cas particulier $V_{IN} = 2.7 \text{ V}$, calculer le nombre numérique D_{MSB} présent à la sortie du CAN1 (nous arrondirons à la valeur immédiatement inférieure).
- Calculer V₃, la tension de sortie du CNA. En déduire V₄, la tension d'entrée du CAN2.
- Calculer le nombre numérique **D**_{LSB} présent à la sortie du CAN2.
- En déduire la donnée D, résultat de la conversion à la sortie du registre.

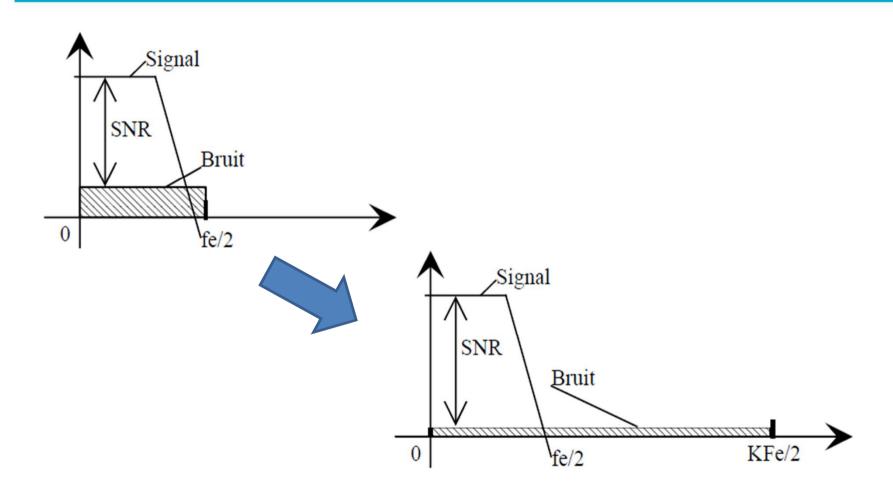
ARCHITECTURES: Pipeline





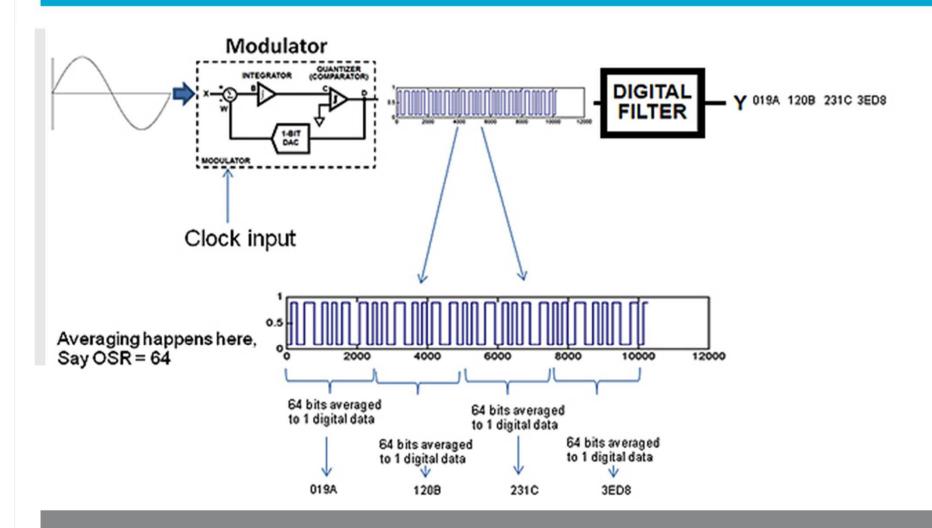
ARCHITECTURES: Sigma Delta





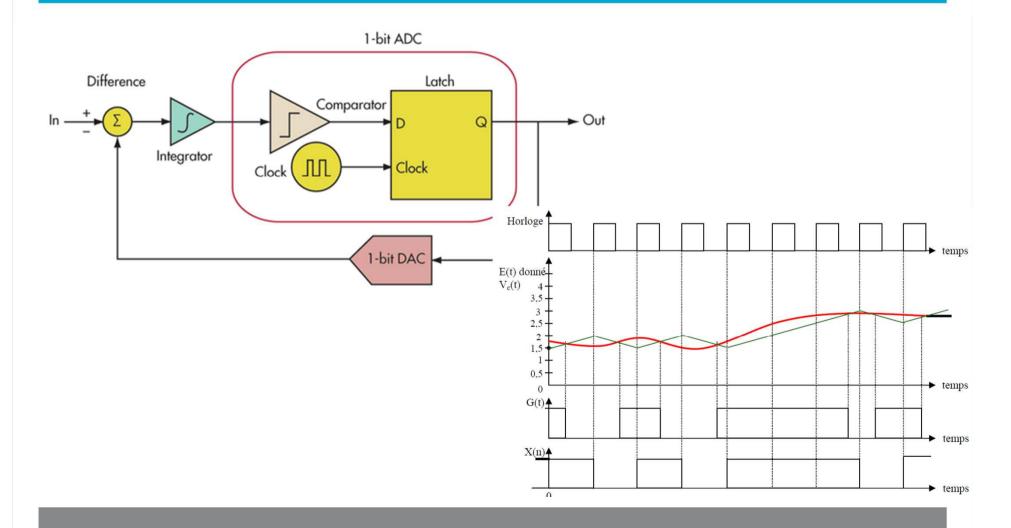
ARCHITECTURES: Sigma Delta





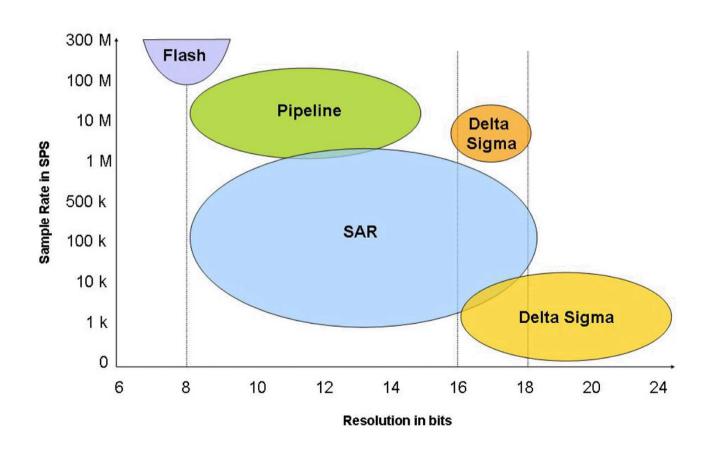
ARCHITECTURES: Sigma Delta





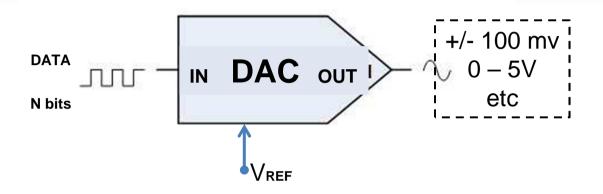
ARCHITECTURES: Comparaison

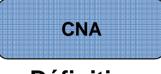




LES CNA (ou DAC)







Définitions

Q (Quantum) ou LSB (Last Significant Bit) => Résolution

$$1 LSB = FSR/(2^n - 1)$$

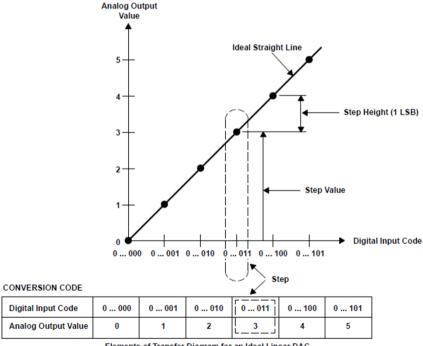
Tension de pleine échelle (FSR) vs Tension de référence (VREF)

LES CNA (ou DAC)





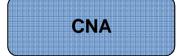
CNA



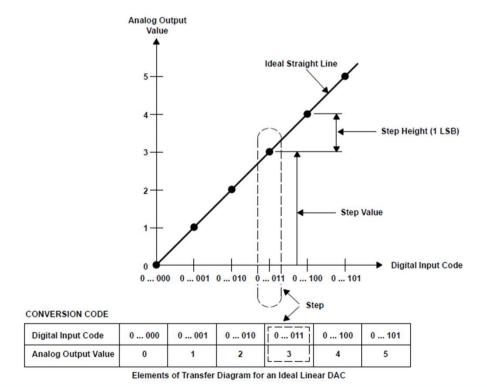
Elements of Transfer Diagram for an Ideal Linear DAC

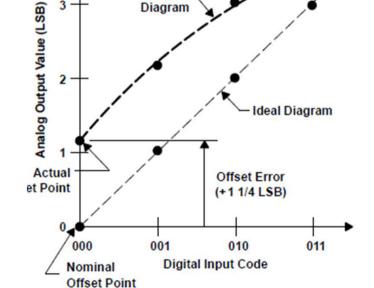
LES CNA(ou DAC)





Erreur de décalage





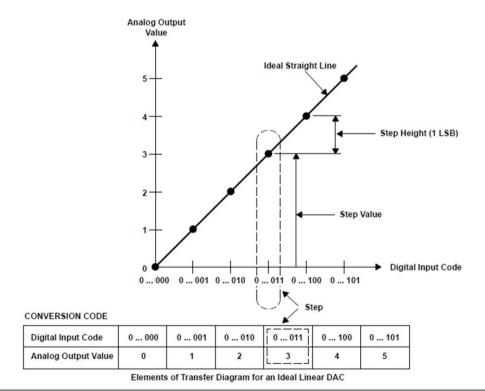
Actual Diagram

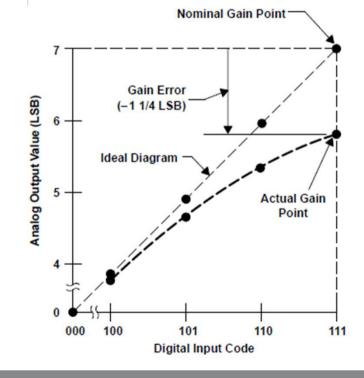
LES CNA(ou DAC)





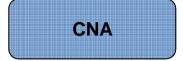
Erreur de Gain



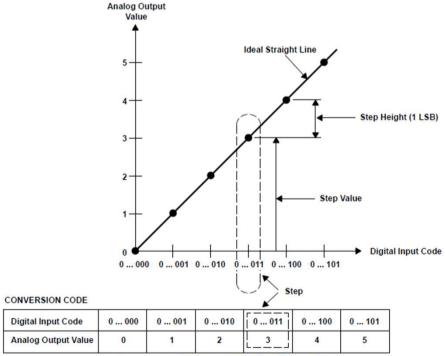


LES CNA(ou DAC)

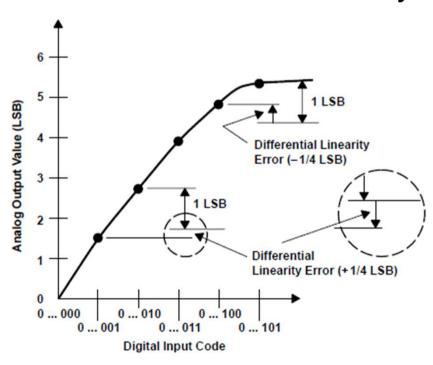




DNL: Differential Non Linearity

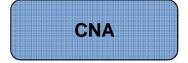




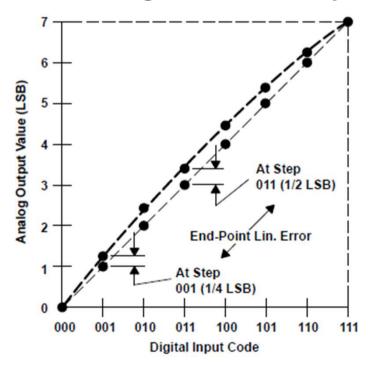


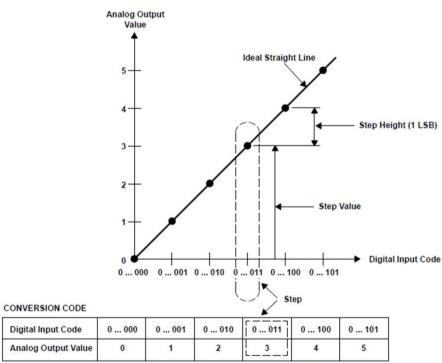
LES CNA(ou DAC)





INL: Integral Non Linearity





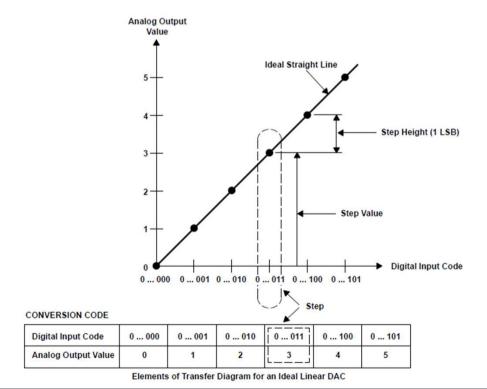
Elements of Transfer Diagram for an Ideal Linear DAC

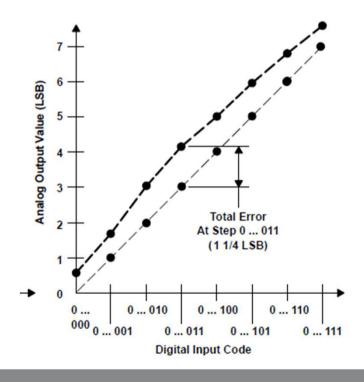
LES CNA(ou DAC)





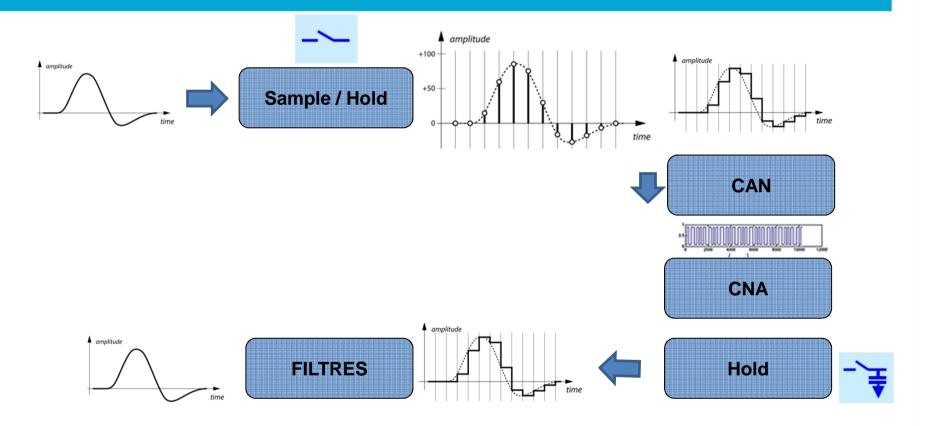
Total Error (Absolute Accuracy)





Retour sur l'échantillonage





DAC du C8051F020



Table 8.1. DAC Electrical Characteristics

VDD = 3.0 V, AV+ = 3.0 V, VREF = 2.40 V (REFBE = 0), No Output Load unless otherwise specified

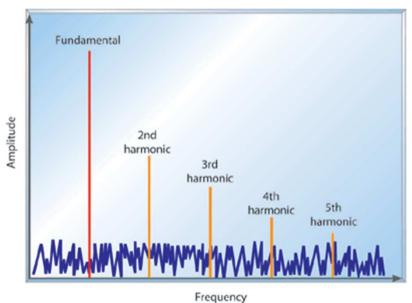
| CONDITIONS | MIN | TYP | MAX | UNITS |
|---|---|--|---------------|--------|
| • | ie . | • | ' | |
| | 12 | | bits | |
| | | ±2 | | LSB |
| | | | ±l | LSB |
| No Output Filter 100 kHz Output Filter 10 kHz Output Filter | | 250 128 41 | | μVrms |
| Data Word = 0x014 | | ±3 | ±30 | mV |
| | | 6 | | ppm/°C |
| | | ±20 | ±60 | mV |
| | | 10 | | ppm/°C |
| | | -60 | | dB |
| DACnEN = 0 | | 100 | | kΩ |
| | | 300 | | μA |
| Data Word = 0xFFF | | 15 | | mA |
| • | | | | |
| Load = 40pF | | 0.44 | | V/µs |
| Load = 40pF, Output swing from code 0xFFF to 0x014 | | 10 | | μs |
| | 0 | | VREF- 1LSB | V |
| | | 10 | | μs |
| | | | | |
| I _L = 0.01mA to 0.3mA at code 0xFFF | | 60 | | ppm |
| h DAC) | | | | |
| Data Word = 0x7FF | | 110 | 400 | μА |
| | 100 kHz Output Filter 10 kHz Output Filter Data Word = 0x014 DACnEN = 0 Data Word = 0xFFF Load = 40pF Load = 40pF, Output swing from code 0xFFF to 0x014 I _L = 0.01mA to 0.3mA at code 0xFFF | 100 kHz Output Filter 10 kHz Output Filter Data Word = 0x014 DACnEN = 0 Data Word = 0xFFF Load = 40pF Load = 40pF, Output swing from code 0xFFF to 0x014 0 I _L = 0.01mA to 0.3mA at code 0xFFF | ±2 | ±2 |

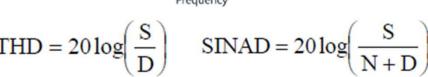
Performances

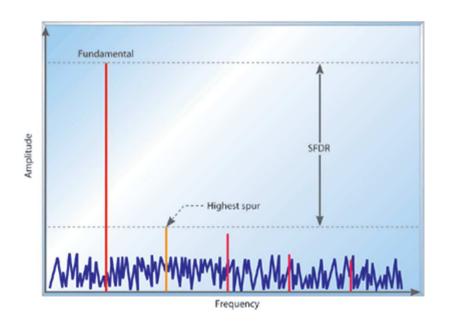


– Dynamiques : SNR - THD – SINAD - SFDR

$$SNR = 20 \log \left(\frac{S}{N}\right),$$







Performances



Dynamiques : Settling time, Voltage swing

DAC du C8051F020



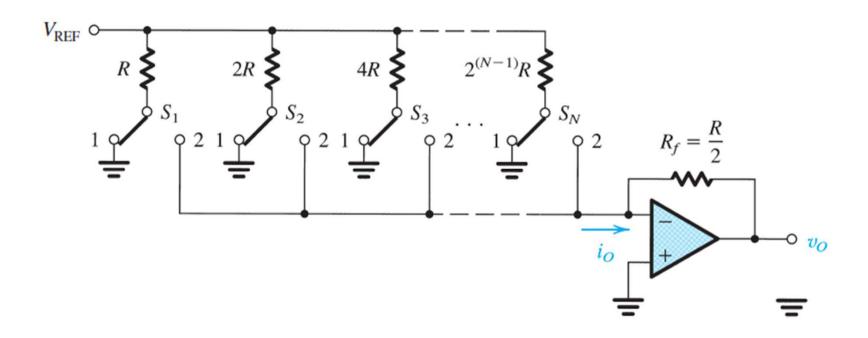
Table 8.1. DAC Electrical Characteristics

VDD = 3.0 V, AV+ = 3.0 V, VREF = 2.40 V (REFBE = 0), No Output Load unless otherwise specified

| PARAMETER | CONDITIONS | MIN | TYP | MAX | UNITS |
|---|---|-----|------------------|---------------|--------|
| STATIC PERFORMANCE | • | • | | • | |
| Resolution | | 12 | | bits | |
| Integral Nonlinearity | | | ±2 | | LSB |
| Differential Nonlinearity | | | | ±l | LSB |
| Output Noise | No Output Filter 100 kHz Output Filter 10 kHz Output Filter | | 250 128 41 | | μVrms |
| Offset Error | Data Word = 0x014 | | ±3 | ±30 | mV |
| Offset Tempco | | | 6 | | ppm/°C |
| Gain Error | | | ±20 | ±60 | mV |
| Gain-Error Tempco | | | 10 | | ppm/°C |
| VDD Power Supply Rejection Ratio | | | -60 | | dВ |
| Output Impedance in Shutdown Mode | DACnEN = 0 | | 100 | | kΩ |
| Output Sink Current | | | 300 | | μA |
| Output Short-Circuit Current | Data Word = 0xFFF | | 15 | | mA |
| DYNAMIC PERFORMANCE | <u> </u> | | | | |
| Voltage Output Slew Rate | Load = 40pF | | 0.44 | | V/µs |
| Output Settling Time to 1/2 LSB | Load = 40pF, Output swing from code 0xFFF to 0x014 | | 10 | | μs |
| Output Voltage Swing | | 0 | | VREF- 1LSB | v |
| Startup Time | | | 10 | | μs |
| ANALOG OUTPUTS | | | | | |
| Load Regulation | I _L = 0.01mA to 0.3mA at code 0xFFF | | 60 | | ppm |
| POWER CONSUMPTION (eac | h DAC) | | | | |
| Power Supply Current (AV+ sup- plied to DAC) | Data Word = 0x7FF | | 110 | 400 | μА |
| | | | | | |

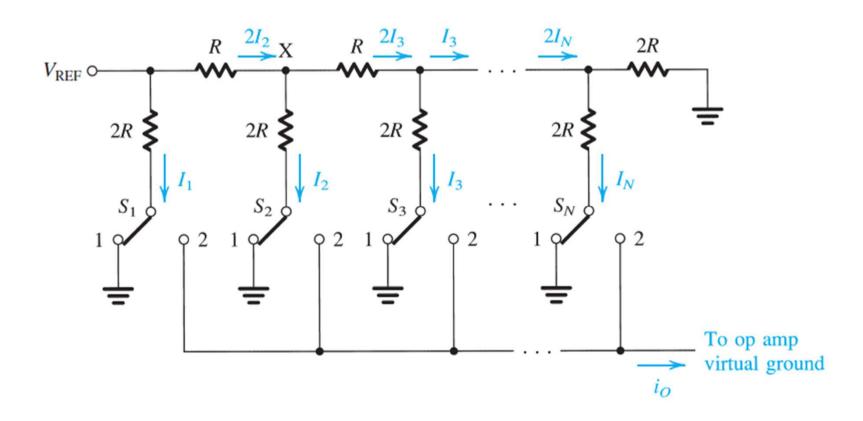
ARCHITECTURES : R pondérées





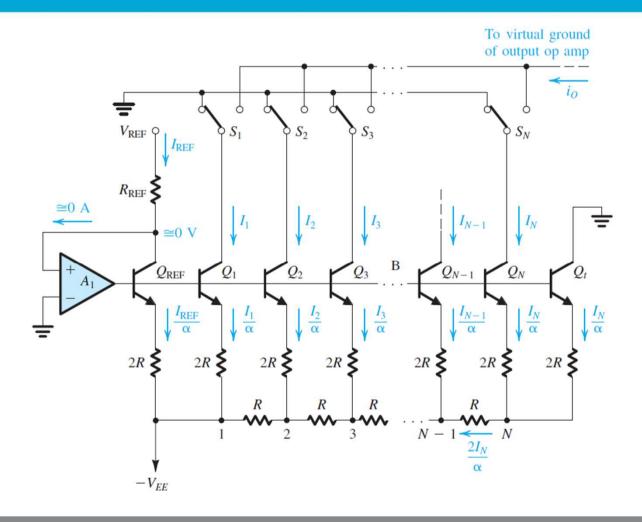
ARCHITECTURES: R-2R





ARCHITECTURES : Courants pondérés





Références bibliographiques



- [1] Len Satller, Silicon labs, Application Notes
- [2] Understanding Data converters, Application report, Texas Instruments



MERCI DE VOTRE ATTENTION!

L. LABRAK



